Session Program

3–5 Jun 2020

36th RD50 Workshop (CERN - - online Workshop)

Defect Characterization

Wednesday 3 June

10:00

Defect Characterization: Defect and Material Characterization

Session | **Location:** Virtual meeting at CERN

10:00–10:20

Quantum characteristics of electron and hole quasiparticles in silicon defects

Speaker
Prof. Darius Abramavicius

10:20–10:40

Electron mobility dependence on neutron and electron irradiation fluence in Si

Speaker
Prof. Juozas Vaitkus

10:40–11:00

Update on Radiation damage investigation of epitaxial P type Silicon using Schottky / pn junctions and LGAD - GaN activities at RAL

Speaker
Enrico Giulio Villani

11:00–11:20 **Break**

11:20–11:40

DLTS and TSC techniques: A brief introduction

Speaker
Anja Himmerlich

11:40–12:00

Defect characterization in boron doped silicon sensors after exposure to protons, neutrons and electrons

Speaker
Yana Gurimskaya

12:00–12:20

DLTS studies on as irradiated PiN diodes of different resistivity

Speaker
Ioana Pintilie

12:20–12:40

Discussion Session: Defect Characterization & Acceptor Removal

Speaker
Ioana Pintilie

13:00